

Title (en)
COIN TESTING APPARATUS

Publication
EP 0213283 B1 19900228 (DE)

Application
EP 86107405 A 19860531

Priority
CH 325485 A 19850726

Abstract (en)
[origin: WO8700662A1] To verify the diameter of a coin, several inductive probes (11, 12, 13) are arranged, one for each section of the coin diameter used for the verification. Each of these probes (e.g. 11) is so arranged that it is influenced to a greater or smaller extent by coins (e.g. 4) whose diameter lies in the region which is attributed to it (11), whereas it is not influenced by coins whose diameter lies under this region and is influenced to a maximum extent by coins (e.g. 5) whose diameter lies above this region irrespective of this diameter. The signal produced by the coin being verified on the probe in whose section its diameter lies is compared with memorized comparison signals for coins that can be accepted.

IPC 1-7
G07D 5/02; G07D 5/08; G07D 5/10; G07F 3/02

IPC 8 full level
G07D 5/00 (2006.01); **G07D 5/02** (2006.01); **G07D 5/08** (2006.01); **G07D 5/10** (2006.01)

CPC (source: EP US)
G07D 5/005 (2013.01 - EP US); **G07D 5/02** (2013.01 - EP US); **G07D 5/08** (2013.01 - EP US)

Cited by
EP0364079A3; EP0367921A3; EP0704825A1; EP0508560A3; US5337877A; US6398001B1; WO9102334A1

Designated contracting state (EPC)
AT CH DE FR GB IT LI

DOCDB simple family (publication)
WO 8700662 A1 19870129; AT E50654 T1 19900315; CA 1250919 A 19890307; CH 667546 A5 19881014; DE 3669215 D1 19900405; EP 0213283 A1 19870311; EP 0213283 B1 19900228; EP 0231219 A1 19870812; EP 0231220 A1 19870812; US 4742903 A 19880510; US 4819780 A 19890411; WO 8700661 A1 19870129; YU 128886 A 19891231

DOCDB simple family (application)
CH 8600106 W 19860725; AT 86107405 T 19860531; CA 512335 A 19860624; CH 325485 A 19850726; CH 8600105 W 19860725; DE 3669215 T 19860531; EP 86107405 A 19860531; EP 86904067 A 19860725; EP 86904068 A 19860725; US 4334687 A 19870325; US 87607886 A 19860619; YU 128886 A 19860718